

EECS 210
 Fall 2006
 Tu, Th 12:30-2
 400 Cory

Applied Electromagnetic Theory
 Office Hours
 M, (W), 11AM
 Tu, Th, (F) 10AM

Prof. A. R. Neureuther,
 509 Cory Hall, 2-4590
 neureuth@eecs



Homework # 9: Due 5PM Friday, Nov 30th

9.1) **Scattering at Long Wavelengths:** Consider both a dielectric with $\epsilon_r = 2$ and a perfectly conducting sphere of radius a . A plane wave is incident in the $+z$ direction with electric field in the x direction.

- Evaluate **the bracket** [] in equation 10.2 of Jackson for the following four combinations of orientation of the electric field and position (orientation, position). $(x, -z)$, $(x, +z)$, $(x, +y)$ and $(y, +x)$ when \mathbf{p} is in the x direction and \mathbf{m} is in the y direction.
- For the spheres evaluate $\mathbf{p}_{\text{Dielectric}}$, \mathbf{p}_{PEC} and \mathbf{m}_{PEC} .
- Evaluate **the bracket** [] in equation 10.2 of Jackson for the dielectric sphere and the metallic sphere for the orientations and positions in part a).
- Make a table of the values from part c) and comment on 1) the coherence of the interaction between \mathbf{p}_{PEC} and \mathbf{m}_{PEC} , 2) the front to back asymmetry in the metallic case, and 3) the non-zero scattering in the y direction for the metallic sphere.

9.2) **Imaging:** An optical projection printer has a wavelength of 193 nm and numerical aperture of $\sin\theta = 0.5$. The mask is 4 times larger (16 times the area) of the image at the wafer and has lines with a 50% duty cycle so that the opaque linewidth equals the open linewidth. Start by neglecting vector effects. **(In a resist with $n = 1.7$ the angle becomes $\text{Sin}\theta = 0.85/1.7 = 0.5$)**

- Draw a k -vector diagram with radius NAk_0 and find the minimum pitch on the wafer for which an on-axis ray will produce 3-wave imaging.
- For the 3-wave imaging in a) determine the contrast $C = (I_{\text{max}} - I_{\text{min}})/(I_{\text{max}} + I_{\text{min}})$. (Hint: Find the E field from plane waves and use $I = EE^*$.)
- Find the maximum off-axis angle, pitch and contrast for two-wave off-axis imaging. (Hint: The two waves E_1 and E_0 are unequal.)
- A 0 and 180 degree phase shifting mask is introduced and illuminated on-axis. Show that this doubles the resolution of problem a) and also produces a contrast of 1.
- Find the contrast C when vector effects are added on the wafer side. (Hint: Due to lack of co-linearity of vectors the maximum decreases and the minimum increases.)

9.3) **Planewave Standing Waves:** Consider a film of thickness d with refractive index 2 on a substrate with refractive index 4. Use the equation in slide 4 of lecture 25 to evaluate the field inside the film at a depth z .

- Derive this formula by considering the multiple scattering waves. (You must consider both the downward and upward waves and correct them for their phases at depth z . First consider the dominant downward and then the dominant upward waves. Then add the 2nd most dominant downward and upward and notice that they differ from the dominant waves by a common round trip factor z . Then use $1 + z + z^2 + \dots = 1/(1-z)$. Finally use the fact that $\rho_{12} = -\rho_{21}$.)
- Make a spot check that the formula is correct by making the film thickness $\lambda/4$ to produce quarter wave matching which makes $E_2 = E_1$ at $z = 0$.
- Evaluate the accuracy for just the dominant downward and upward waves (numerator) compared to including the infinite reflections (full expression).
- Show that $E_{2\text{max}}/E_{2\text{min}}$ is independent of d and given by $(1+\rho_{23})/(1-r_{23})$